

Notice of References Cited	Application/Control No. 10/664,152	Applicant(s)/Patent Under Reexamination AOKI, KENTAROH	
	Examiner Dung Nguyen	Art Unit 2871	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0101550 A1	08-2002	Yeh, Chun-Lin	349/65
	B	US-			
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	D	US-			
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FOREIGN PATENT DOCUMENTS

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